

Test Report No:
2610095R-RFJPV03S-A

TEST REPORT

Japan Rules & Regulations

Product Name	PanaCast U30
Brand Name	Jabra
Model No.	VSM060
Applicant's Name / Address	GN Audio Japan Ltd. Shinbashi M-SQUARE7 floor, 1-chome 10th No. 6, Shinbashi, Minato-ku, Tokyo, Japan
Manufacturer's Name	GN Hearing A/S
Test Method Requested, Standard	Item 19-3 of Article 2 Paragraph 1 Notification No. 88 of MIC, 2004, Annex 45.
Verdict Summary	IN COMPLIANCE
Documented By Ida Tung	<i>Ida Tung</i>
Approved By Steven Tsai	<i>Steven Tsai</i>
Date of Receipt	2026/01/06
Date of Issue	2026/04/16
Report Version	V1.0

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Competences and Guarantees

DEKRA is a testing laboratory competent to carry out the tests described in this report.

In order to assure the traceability to other national and international laboratories, DEKRA has a calibration and maintenance program for its measurement equipment.

DEKRA guarantees the reliability of the data presented in this report, which is the result of the measurements and the tests performed to the item under test on the date and under the conditions stated in the report and it is based on the knowledge and technical facilities available at DEKRA at the time of performance of the test.

DEKRA is liable to the client for the maintenance of the confidentiality of all information related to the item under test and the results of the test.

The results presented in this Test Report apply only to the particular item under test established in this document.

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General Conditions

1. The test results relate only to the samples tested.
2. The test results shown in the test report are traceable to the national/international standard through the calibration report of the equipment and evaluated measurement uncertainty herein.
3. This report must not be used to claim product endorsement by TAF or any agency of the government.
4. The test report shall not be reproduced without the written approval of DEKRA Testing and Certification Co., Ltd.
5. Measurement uncertainties evaluated for each testing system and associated connections are given here to provide the system information for reference. Compliance determinations do not take into account measurement uncertainties for each testing system, but are based on the results of the compliance measurement.

Revision History

Version	Description	Issued Date
V1.0	Initial issue of report	2026/04/16

Summary of Test Result

Report Clause	Test Items	Result (PASS/FAIL)	Remark
3	Antenna Power, Antenna Power Tolerance and E.I.R.P	PASS	-
4	Occupied Bandwidth	PASS	-
5	Frequency Tolerance	PASS	-
6	Adjacent Channel Emitted power and Out-Band Leakage Power	PASS	-
7	Transmitter Spurious Emissions	PASS	-
8	Receiver Spurious Emissions	PASS	-
9	Carrier Sensing	PASS	-
10	Transmission burst length	PASS	-
11	Interference Prevention Function	PASS	-

Comments and Explanations

The declared of product specification for EUT presented in the report are provided by the manufacturer, and the manufacturer takes all the responsibilities for the accuracy of product specification.

1. General Information

1.1. EUT Description

Frequency Range	5150 ~ 5250 MHz 5250 ~ 5350 MHz 5470 ~ 5725 MHz			
Operating Frequency / Channel Number	IEEE 802.11a/n/ac/ax (20 MHz)	5180 ~ 5240 MHz / 4 Channels 5260 ~ 5320 MHz / 4 Channels 5500 ~ 5720 MHz / 12 Channels		
	IEEE 802.11n/ac/ax (40 MHz)	5190 ~ 5230 MHz / 2 Channels 5270 ~ 5310 MHz / 2 Channels 5510 ~ 5710 MHz / 6 Channels		
	IEEE 802.11ac/ax (80 MHz)	5210 MHz / 1 Channel 5290 MHz / 1 Channel 5530 ~ 5690 MHz / 3 Channels		
	IEEE 802.11ac/ax (160 MHz)	5250 MHz / 1 Channel 5570 MHz / 1 Channel		
Type of Modulation	IEEE 802.11a/n	OFDM-BPSK, QPSK, 16QAM, 64QAM		
	IEEE 802.11ac	OFDM-BPSK, QPSK, 16QAM, 64QAM, 256QAM		
	IEEE 802.11ax	OFDMA-BPSK, QPSK, 16QAM, 64QAM, 256QAM, 1024QAM		
Declared Antenna Power		W52	W53	W56
	802.11a (20 MHz)	3.1477 mW/MHz	2.7542 mW/MHz	2.6915 mW/MHz
	802.11ax (20 MHz)	2.4547 mW/MHz	1.9011 mW/MHz	1.9143 mW/MHz
	802.11ax (40 MHz)	1.1169 mW/MHz	1.1508 mW/MHz	0.9863 mW/MHz
	802.11ax (80 MHz)	0.4842 mW/MHz	0.4688 mW/MHz	0.4571 mW/MHz
	802.11ax (160 MHz)	0.2307 mW/MHz	-- mW/MHz	0.2350 mW/MHz

Accessories Information					
No.	Equipment Name	Brand Name	Model No.	Rating	Remark
1	Adapter	Wang Huei Electronic Technology Co. Ltd	WH-1204000	INPUT: AC 100-240V~50/60Hz OUTPUT: 12.0V  4.0A 48W 0.6A	With power cable: Non-shielded, 2m
No.	Equipment Name		Description		
2	Type C to Type C Cable		Shielded, 1.8m		
3	HDMI Cable (option)		Shielded, 1.8m with two ferrite cores bonded.		
4	Power Cable		Non-shielded, 1m		

Antenna Information					
Item.	Brand Name	Model No.	Type	Antenna Gain (dBi)	
1	SPEED	F-0Q-51-6010-004-00	PIFA	U-NII 1	4.08
				U-NII 2A	4.08
				U-NII 2C	5.33

For IEEE 802.11a/n/ac/ax Mode: (1TX, 1RX)

1.2. EUT Information

EUT Power Type	From Adapter			
EUT Function	☒	Point-to-multipoint	☐	Point-to-point
Weather Band (5600 ~ 5650 MHz)	☒	With 5600 ~ 5650 MHz	☐	Without 5600 ~ 5650 MHz
Beamforming Function	☐	With beamforming	☒	Without beamforming
Resource Unit of 802.11ax	☒	Full RU	☐	Partial RU
Operating Mode	☐	Master		
	☐	Slave with radar detection		
	☒	Slave without radar detection		

1.3. Testing Location Information

Site Description	Accredited by TAF
	Accredited Number: 3023

Test Laboratory	DEKRA Testing and Certification Co., Ltd.
	Linkou Laboratory
Address	No. 85, Wenlin St., Linkou Dist., New Taipei City 244017, Taiwan, R.O.C.
Performed Location	No. 26, Huaya 1st Rd., Guishan Dist., Taoyuan City 333411, Taiwan, R.O.C.
Phone Number	+886-3-275-7255
Fax Number	+886-3-327-8031

Performed Item	Items	Required	Actual	Test Date	Tested By
RF Conducted Emission	Temperature (°C)	5~35 °C	22.2~24.2°C	2026/03/23 ~	Neko Chen
	Humidity (%RH)	45~85 %	64.7~70.4%	2026/03/30	Jimmy Chang

1.4. Measurement Uncertainty

Uncertainties have been calculated according to the DEKRA internal document.

The reported expanded uncertainties are based on a standard uncertainty multiplied by a coverage factor of $k=2$, providing a level of confidence of approximately 95%.

Measurement uncertainties evaluated for each testing system and associated connections are given here to provide the system information for reference. Compliance determinations do not take into account measurement uncertainties for each testing system, but are based on the results of the compliance measurement.

Test Item	Uncertainty
Antenna Power, Antenna Power Tolerance and E.I.R.P	Spectrum Analyzer: ± 2.13 dB Power Meter: ± 1.05 dB
Occupied Bandwidth	± 1580.61 Hz
Frequency Tolerance	± 1580.61 Hz
Transmitter Spurious Emissions	± 2.13 dB
Adjacent Channel Emitted Power	± 2.13 dB
Out-Band Leakage Power	± 2.13 dB
Receiver Spurious Emissions	± 2.13 dB
Carrier Sensing	± 0.62 %
Transmission burst length	± 0.62 %
Interference Prevention Function	N/A

1.5. List of Test Equipment

For Conducted Measurements / HY-SR02

	Equipment	Manufacturer	Model No.	Serial No.	Cal. by	Cal. Method	Cal. Date	Due Date
V	Spectrum Analyzer	R&S	FSV30	103465	ETC	*(c)	2025/06/13	2026/06/12
V	Power Meter	Anritsu	ML2496A	1548003	ETC	*(c)	2025/12/15	2026/12/14
V	Power Sensor	Anritsu	MA2411B	1531024	ETC	*(c)	2025/12/15	2026/12/14
V	Power Sensor	Anritsu	MA2411B	1531025	ETC	*(c)	2025/12/15	2026/12/14
V	Spectrum Analyzer	KEYSIGHT	N9010A	MY55150401	ETC	*(c)	2025/11/27	2026/11/26
V	Analog Signal Generator	Agilent	E8257D	MY44320633	ETC	*(c)	2025/07/23	2026/07/22

Note:

1. All equipment is calibrated every year.
2. The test instruments marked with "V" are used to measure the final test results.
3. Test Software Version: DEKRA Conduction Test System V9.0.6
4. a) Calibration conducted by the National Institute of Information and Communications Technology(NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated agency under Article 102-18 paragraph (1).
d) Calibration conducted by using other equipment that listed above from a) to c).

2. Test Configuration of EUT

2.1. Test Condition

EUT Operational Condition	
Testing Voltage	AC 100V/50Hz

2.2. Test Frequency Mode

Test Software Version	QRCT4 / Version 4.0.211.0
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Modulation	Frequency (MHz)	Power Setting
802.11a (20 MHz)	5180	14.5
	5220	15
	5240	15
	5260	14.5
	5300	14.5
	5320	14.5
	5500	14.5
	5600	15
	5700	15
	5720	15
802.11ax (20 MHz)	5180	14.5
	5220	14.5
	5240	14.5
	5260	14
	5300	14
	5320	14
	5500	14
	5600	14
	5700	14
	5720	14

Modulation	Frequency (MHz)	Power Setting
802.11ax (40 MHz)	5190	14
	5230	14
	5270	14
	5310	14
	5510	14
	5590	14
	5670	14
	5710	14
802.11ax (80 MHz)	5210	13
	5290	13
	5530	13
	5610	13
	5690	13
802.11ax (160 MHz)	5250	13.5
	5570	13.5

2.3. Test Conditions

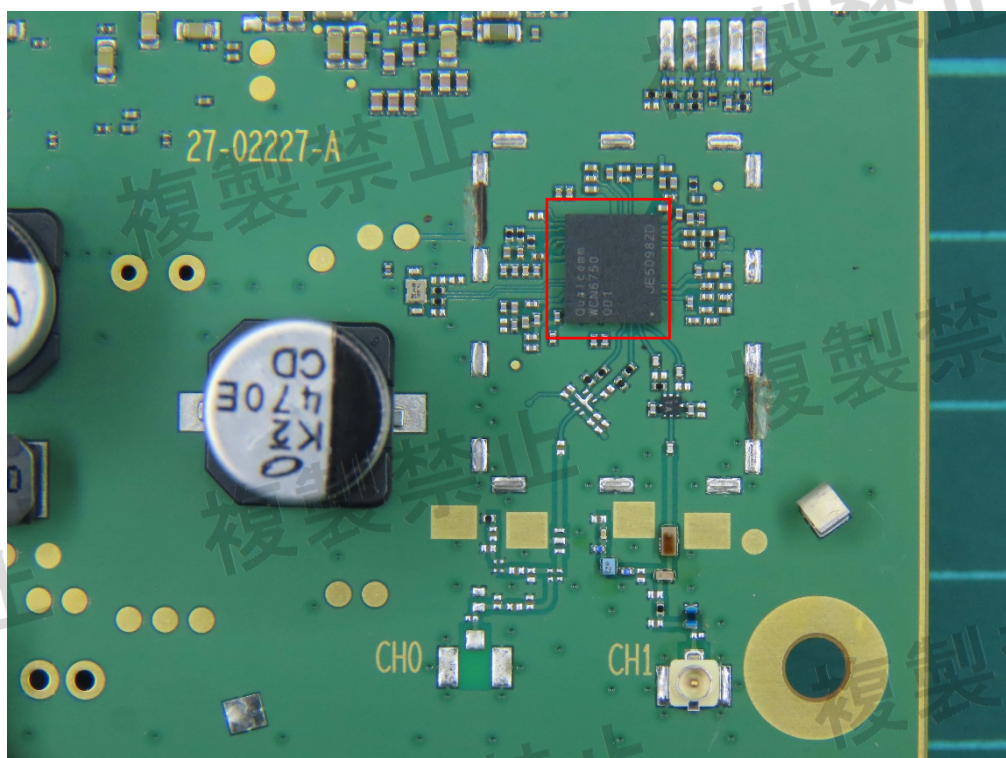
Voltage Test Item	Test Voltage	Voltage meter reading value
Nominal Voltage	AC 100V	DC 3.57V
Highest Voltage	AC 110V	DC 3.57V
Lowest Voltage	AC 90V	DC 3.57V

Note: 1. The Voltage supply for RF Chip Pin 8 is DC 3.57V.

2. The internal supply gives a fluctuation value less than 1 % (Around 0.0% from max. to min.)

2.4. RF and IF section must be tamper requirement

Requirement	Comments	Result
RF, IF and Modulation section must be tamper	☐ Use Special Screw ☐ Metal Shielding is Soldered ☒ Use Ball Grid Array (BGA)	Complete
	☒ RF module/Chip pin >10 ☒ RF module/Chip pins distance <1.5mm	Complete



2.5. Measurement Configuration

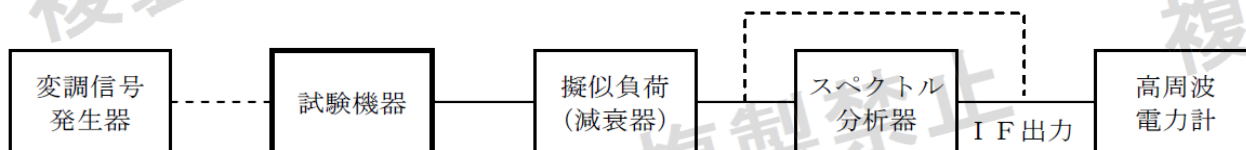
Test Mode	Mode 1 (Transmit)	802.11a (20 MHz)
		802.11ax (20 MHz)
		802.11ax (40 MHz)
		802.11ax (80 MHz)
		802.11ax (160 MHz)

Note:

1. After checking the fluctuation of input voltage to the circuit of the radio part (excluding the power supply) of the equipment to be tested, the fluctuation less than $\pm 1\%$ when input voltage from an external supply into the equipment fluctuates $\pm 10\%$, therefore, the test is carried out only at the normal voltage.
2. Determining compliance shall be based on the results of the compliance measurement, without taking measurement instrumentation uncertainty into account.
3. The lowest data rates are tested in each mode. Only the worst case is shown in the report.
(802.11a is 6 Mbps, 802.11ax is MCS0)

3. Antenna Power, Antenna Power Tolerance and E.I.R.P

3.1. Test Setup



3.2. Test Limit

Antenna Power:

For 20 MHz Bandwidth: $\leq 10\text{mW/MHz}$

For 40 MHz Bandwidth: $\leq 5\text{mW/MHz}$

For 80 MHz Bandwidth: $\leq 2.5\text{mW/MHz}$

For 160 MHz Bandwidth: $\leq 1.25\text{mW/MHz}$

Antenna Power Tolerance:

For 20 MHz, 40 MHz, 80MHz and 160 MHz Bandwidth in W52, W53 Bands: +20% to -80%

For 20 MHz, 40 MHz, 80MHz and 160 MHz Bandwidth in W56 Band: +50% to -50%

EIRP:

For 20 MHz Bandwidth in W52 Band: $\leq 10\text{mW/MHz}$

For 20 MHz Bandwidth in W53 Band: $\leq 10\text{mW/MHz}$ (with TPC); $\leq 5\text{mW/MHz}$ (without TPC)

For 20 MHz Bandwidth in W56 Band: $\leq 50\text{mW/MHz}$ (with TPC); $\leq 25\text{mW/MHz}$ (without TPC)

For 40 MHz Bandwidth in W52 Band: $\leq 5\text{mW/MHz}$

For 40 MHz Bandwidth in W53 Band: $\leq 5\text{mW/MHz}$ (with TPC); $\leq 2.5\text{mW/MHz}$ (without TPC)

For 40 MHz Bandwidth in W56 Band: $\leq 25\text{mW/MHz}$ (with TPC); $\leq 12.5\text{mW/MHz}$ (without TPC)

For 80 MHz Bandwidth in W52 Band: $\leq 2.5\text{mW/MHz}$

For 80 MHz andwidth in W53 Band: $\leq 2.5\text{mW/MHz}$ (with TPC); $\leq 1.25\text{mW/MHz}$ (without TPC)

For 80 MHz Bandwidth in W56 Band: $\leq 12.5\text{ mW/MHz}$ (with TPC); $\leq 6.25\text{mW/MHz}$ (without TPC)

For 160 MHz Bandwidth in W52 Band: $\leq 1.25\text{mW/MHz}$

For 160 MHz andwidth in W53 Band: $\leq 1.25\text{mW/MHz}$ (with TPC); $\leq 0.625\text{mW/MHz}$ (without TPC)

For 160 MHz Bandwidth in W56 Band: $\leq 6.25\text{ mW/MHz}$ (with TPC); $\leq 3.125\text{mW/MHz}$ (without TPC)

3.3. Test Method

According to Temporary test method specified by KIWA.

3.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the modulated transmitter's radio frequency power Antenna.

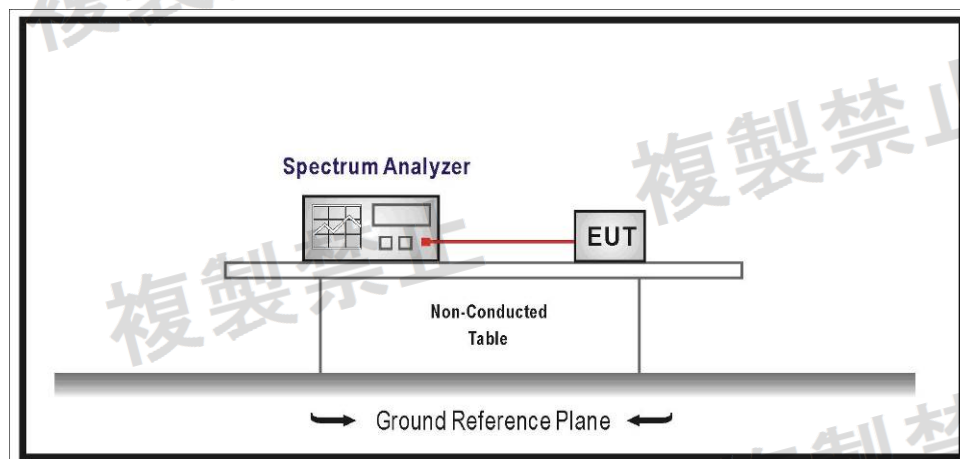
- (1) A measurement instrument with an integrated 1MHz power bandwidth function may be used to automate the test process.
- (2) Connect the power meter to the IF Antenna of the spectrum analyzer.
- (3) Set zero span of spectrum analyzer and 'Maximum Hold' than test result will show in power meter.

3.5. Test Result of Antenna Power, Antenna Power Tolerance and E.I.R.P

Refer as Appendix A

4. Occupied Bandwidth

4.1. Test Setup



4.2. Test Limit

20 MHz Bandwidth $\leq$ 20MHz

40 MHz Bandwidth $\leq$ 40MHz

80 MHz Bandwidth $\leq$ 80MHz

160 MHz Bandwidth $\leq$ 160MHz

4.3. Test Method

According to Temporary test method specified by KIWA.

4.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the modulated transmitter's radio frequency power output.

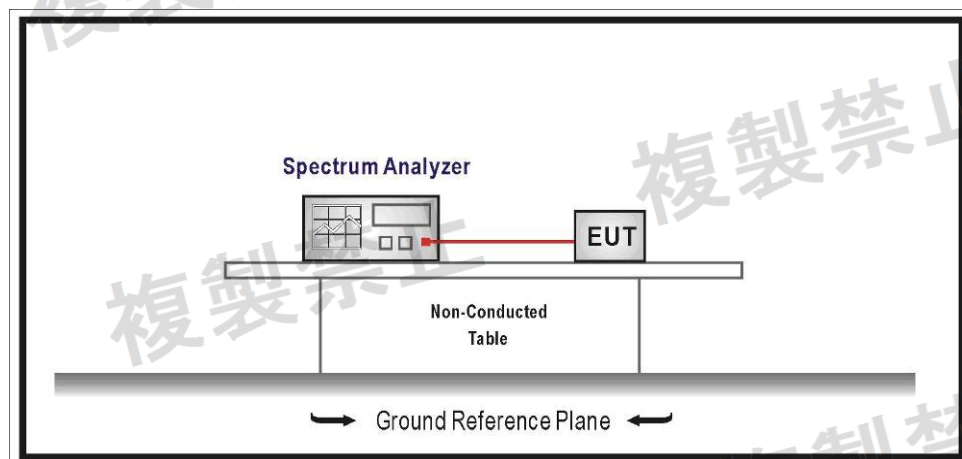
- (a) A positive peak detector function must be used.
- (b) A measurement instrument with an integrated 99% power bandwidth function may be used to automate the test process.
- (c) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.
- (d) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

4.5. Test Result of Occupied Bandwidth

Refer as Appendix B

5. Frequency Tolerance

5.1. Test Setup



5.2. Test Limit

± 20 ppm

5.3. Test Method

According to Temporary test method specified by KIWA.

5.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the unmodulated transmitter's radio frequency power output.

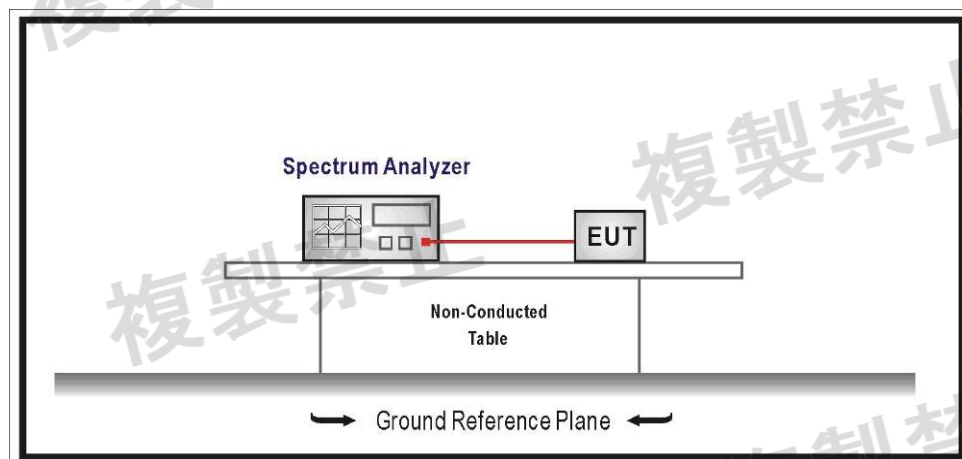
- (a) A positive peak detector function must be used.
- (b) The measurement instrument bandwidth and span must be set sufficiently wide, and the scan time set sufficiently slowly, to ensure all products of the unmodulated signal are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.
- (c) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

5.5. Test Result of Frequency Tolerance

Refer as Appendix C

6. Adjacent Channel Emitted power and Out-Band Leakage Power

6.1. Test Setup



6.2. Test Limit

Adjacent Channel Emitted Power:

802.11a, 802.11-n/ac/ax20 (W52, W53, W56 Band)	802.11-n/ac/ax40 (W52, W53, W56 Band)	802.11-ac/ax80 (W52, W53, W56 Band)
$F_c \pm 20$ MHz -25dBc for ± 10 MHz BW $F_c \pm 40$ MHz -40dBc for ± 10 MHz BW	$F_c \pm 40$ MHz -25dBc for ± 20 MHz BW $F_c \pm 80$ MHz -40dBc for ± 20 MHz BW	$F_c \pm 80$ MHz -25dBc for ± 40 MHz BW

Out-Band Leakage Power:

W52			
20MHz		40MHz	80MHz
OBW : 18MHz or less	OBW : 18 - 20 MHz		
5,142 MHz or less: 2.5 μ W/MHz	5,142 MHz or less: 2.5 μ W/MHz	5,141.6 MHz or less: 2.5 μ W/MHz	5,123.2 MHz or less: 2.5 μ W/MHz
5,142 - 5,150 MHz: 15 μ W/MHz	5,142 - 5,150 MHz: 15 μ W/MHz	5,141.6 - 5,150 MHz: 15 μ W/MHz	5,123.2 - 5,150 MHz: 15 μ W/MHz
	5,250 - 5,250.2 MHz: $10^{1-(8/3)(f-9.75)}$ mW/MHz		
5,250 - 5,251 MHz: $10^{1-(f-9)}$ mW/MHz	5,250.2 - 5,251 MHz: $10^{1-(f-9)}$ mW/MHz	5,250 - 5,251 MHz: $10^{-(f-20)+\log(1/2)}$ mW/MHz	5,250 - 5,251 MHz: $10^{-(f-40)+\log(1/4)}$ mW/MHz
5,251 - 5,260 MHz: $10^{-1-(8/90)(f-11)}$ mW/MHz	5,251 - 5,260 MHz: $10^{-1-(8/90)(f-11)}$ mW/MHz	5,251 - 5,270 MHz: $10^{-(8/190)(f-21)+\log(1/2)}$ mW/MHz	5,251 - 5,290 MHz: $10^{-(8/390)(f-41)+\log(1/4)}$ mW/MHz
5,260 - 5,266.7 MHz: $10^{-1.8-(6/50)(f-20)}$ mW/MHz	5,260 - 5,266.7 MHz: $10^{-1.8-(6/50)(f-20)}$ mW/MHz	5,270 - 5,278.4 MHz: $10^{-(3/50)(f-40)+\log(1/2)}$ mW/MHz	5,290 - 5,296.7 MHz: $10^{-(3/100)(f-80)+\log(1/4)}$ mW/MHz
5,266.7 MHz or more: 2.5 μ W/MHz	5,266.7 MHz or more: 2.5 μ W/MHz	5,278.4 MHz or more: 2.5 μ W/MHz	5,296.7 MHz or more: 2.5 μ W/MHz
f = MHz, Difference from 5240 (MHz)	f = MHz, Difference from 5240 (MHz)	f = MHz, Difference from 5230 (MHz)	f = MHz, Difference from 5210 (MHz)

W53			
20MHz		40MHz	80MHz
OBW : 18MHz or less	OBW : 18 - 20 MHz		
5,233.3 MHz or less: 2.5 μ W/MHz	5,233.3 MHz or less: 2.5 μ W/MHz	5,221.6 MHz or less: 2.5 μ W/MHz	5,203.3 MHz or less: 2.5 μ W/MHz
5,233.3 - 5,240 MHz: $10^{-1.8-(6/50)(f-20)}$ mW/MHz	5,233.3 - 5,240 MHz: $10^{-1.8-(6/50)(f-20)}$ mW/MHz	5,221.6 - 5,230 MHz: $10^{-(3/50)(f-40)+\log(1/2)}$ mW/MHz	5,203.3 - 5,210 MHz: $10^{-(3/100)(f-80)+\log(1/4)}$ mW/MHz
5,240 - 5,249 MHz: $10^{-1-(8/90)(f-11)}$ mW/MHz	5,240 - 5,249 MHz: $10^{-1-(8/90)(f-11)}$ mW/MHz	5,230 - 5,249 MHz: $10^{-(8/190)(f-21)+\log(1/2)}$ mW/MHz	5,210 - 5,249 MHz: $10^{-(8/390)(f-41)+\log(1/4)}$ mW/MHz
5,249 - 5,250 MHz: $10^{1-(f-9)}$ mW/MHz	5,249 - 5,249.8 MHz: $10^{1-(f-9)}$ mW/MHz	5,249 - 5,250 MHz: $10^{-(f-20)+\log(1/2)}$ mW/MHz	5,249 - 5,250 MHz: $10^{-(f-40)+\log(1/4)}$ mW/MHz
5,350 MHz or more: 2.5 μ W/MHz	5,249.8 - 5,250 MHz: $10^{1-(8/3)(f-9.75)}$ mW/MHz	5,350 - 5,358.4 MHz: 15 μ W/MHz	5,350 - 5,376.8 MHz: 15 μ W/MHz
	5,350 MHz or more: 2.5 μ W/MHz	5,358.4 MHz or more: 2.5 μ W/MHz	5,376.8 MHz or more: 2.5 μ W/MHz
f = MHz, Difference from 5260 (MHz)	f = MHz, Difference from 5260 (MHz)	f = MHz, Difference from 5270 (MHz)	f = MHz, Difference from 5290 (MHz)

W56			
20MHz		40MHz	80MHz
DSSS, etc.	OFDM		
5,470 MHz or less: 12.5 μ W/MHz	5,460 MHz or less: 2.5 μ W/MHz	5,460 MHz or less: 12.5 μ W/MHz	5,460 MHz or less: 12.5 μ W/MHz
	5,460 - 5,470 MHz: 12.5 μ W/MHz	5,460 - 5,470 MHz: 50 μ W/MHz	5,460 - 5,469.5 MHz: 50 μ W/MHz
5,730 MHz or more: 12.5 μ W/MHz	5,745 - 5,765 MHz: 12.5 μ W/MHz	5,770 MHz or more: 12.5 μ W/MHz	5,469.5 - 5,470 MHz: 51.2 μ W/MHz
	Over 5,765 MHz: 2.5 μ W/MHz		5,770 MHz or more: 12.5 μ W/MHz

W52 + W53	W56
160MHz	
5,099.6 MHz or less: 2.5 μ W/MHz	5,419.6 MHz or less: 12.5 μ W/MHz
5,099.6 - 5,150 MHz or less: 15 μ W/MHz	5,419.6 - 5,470 MHz: 50 μ W/MHz
5,350 - 5,400.4 MHz or less: 15 μ W/MHz	5,725 MHz or more: 12.5 μ W/MHz
5,400.4 MHz or more: 2.5 μ W/MHz	

6.3. Test Method

According to Temporary test method specified by KIWA.

6.4. Test Procedure

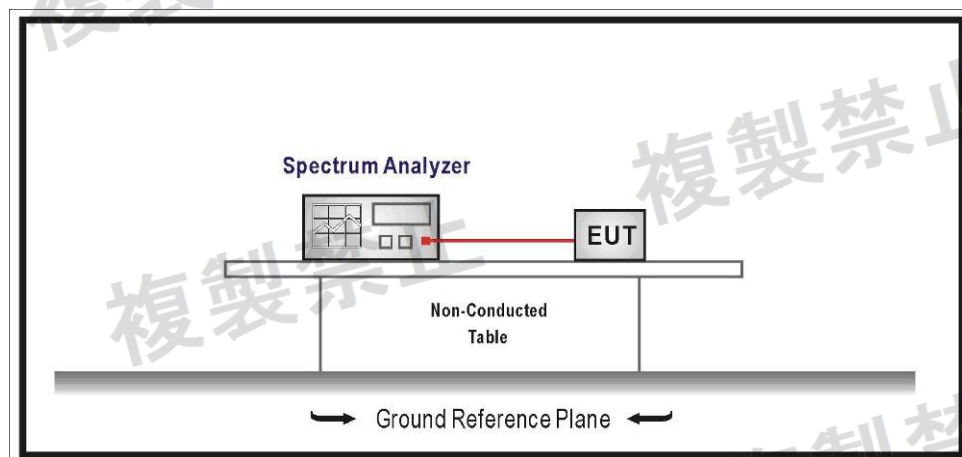
- (a) A spectrum analyzer or similar device shall be used to observe a sample of the modulated transmitter's radio frequency power output
- (b) A positive peak detector function must be used.
- (c) A measurement instrument with an adjacent channel power function may be used to automate the test process.
- (d) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result

6.5. Test Result of Adjacent Channel Emitted power and Out-Band Leakage Power

Refer as Appendix D

7. Transmitter Spurious Emissions

7.1. Test Setup



7.2. Test Limit

$\leq 2.5\mu\text{W}/\text{MHz}$

7.3. Test Method

According to Temporary test method specified by KIWA.

7.4. Test Procedure

The EUT is connected to the spectrum analyzer and it is configured at maximum output power in the different test channels.

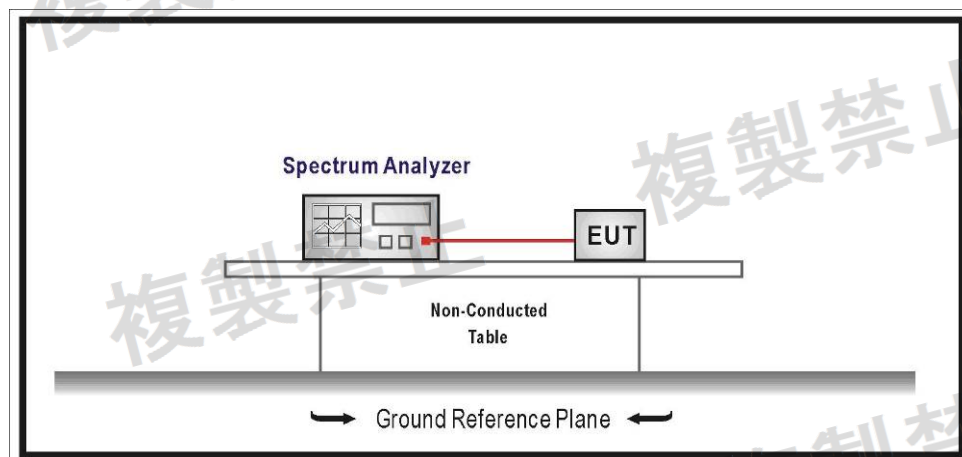
- A positive peak detector function must be used.
- The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slow, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.
- 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

7.5. Test Result of Transmitter Spurious Emissions

Refer as Appendix E

8. Receiver Spurious Emissions

8.1. Test Setup



8.2. Test Limit

$\leq 4\text{nW}$ for $30\text{ MHz} < f < 1000\text{MHz}$

$\leq 20\text{nW}$ for $1000\text{ MHz} \leq f < 26000\text{ MHz}$

8.3. Test Method

According to Temporary test method specified by KIWA.

8.4. Test Procedure

The EUT is connected to the spectrum analyzer and it is configured in reception mode in the different test channels.

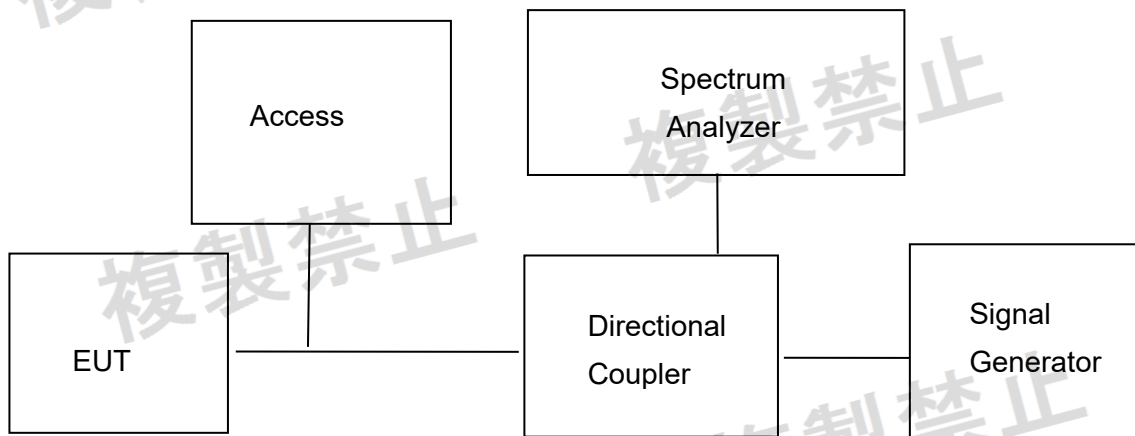
- A positive peak detector function must be used.
- The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.
- 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

8.5. Test Result of Receiver Spurious Emissions

Refer as Appendix F

9. Carrier Sensing

9.1. Test Setup



9.2. Test Limit

Stop transmission while Carrier detecting.

9.3. Test Method

According to Temporary test method specified by KIWA.

9.4. Test Procedure

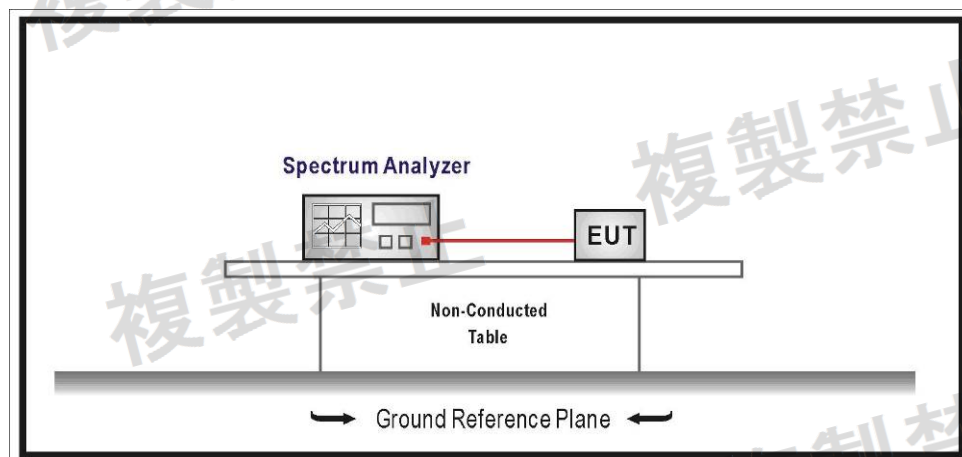
- Link EUT and Access Point to Directional Coupler input port.
- Link Signal Generator and Spectrum Analyzer to test port and output port in the Directional Coupler separately.
- A positive Peak Detector function in Spectrum Analyzer must be used.
- Set the Span to Zero.
- Press the Signal Generator on and it will output the Carrier Signal. When the Link breaks off, wait a minute and press the Signal Generator off. After a while, reset the Link and done the test.

9.5. Test Result of Carrier Sensing

Refer as Appendix G

10. Transmission burst length

10.1. Test Setup



10.2. Test Limit

$\leq 8\text{ms}$

10.3. Test Method

According to Temporary test method specified by KIWA.

10.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the modulated transmitter's radio frequency power output.

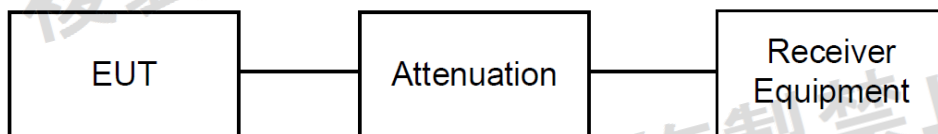
- (a) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.
- (b) 'Clean write' mode may be used.

10.5. Test Result of Transmission burst length

Refer as Appendix H

11. Interference Prevention Function

11.1. Test Setup



11.2. Test Method

According to Temporary test method specified by KIWA.

11.3. Test Procedure

Radio equipment used mainly on the same premises and automatically transmits or receives identification code.

11.4. Test Result of Interference Prevention Function

Refer as Appendix I